

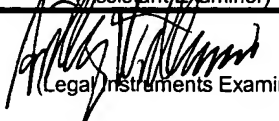


Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/035,528		LEMOFF ET AL.	
	Examiner		Art Unit	
	Shi K. Li		2633	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
398	154								
INTERNATIONAL CLASSIFICATION									
H	0	4	B	10100					
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Shi K. Li 10/27/05 (Assistant Examiner) (Date)		 JASON CHAN SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600 (Chief Examiner) (Date)	Total Claims Allowed: 23	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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